

<b>Notice of References Cited</b>	Application/Control No. 10/571,195		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Patricia Leith		Art Unit 1655	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-			
	D	US-			
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	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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